

<b>Notice of References Cited</b>	Application/Control No. 10/571,866	Applicant(s)/Patent Under Reexamination VEELAERT ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,959,102	09-1999	Wasserman et al.	536/128
*	B	US-6,235,894	05-2001	Kettlitz et al.	536/102
*	C	US-5,346,892	09-1994	Fitt et al.	514/60
*	D	US-5,258,187	11-1993	Shimada, Seinosuke	426/3
*	E	US-5,246,718	09-1993	Haring et al.	426/18
*	F	US-2004/0019014	01-2004	Gustavsson et al.	514/60
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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